



European Organization for Nuclear Research

CINVESTAV – Merida Campus



LCU Meeting

Study of the Heat Load in the LHC

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Introduction

Electron Cloud Build-up

The synchrotron radiation in the LHC creates a continuous flow of photoelectrons. These electrons are accelerated by the electric field of the bunch and hit the vacuum chamber where they create secondary electrons.



Photoemission, residual gas ionization and secondary emission give rise to a quasi-stationary electron cloud inside the beam pipe !!!

Electron cloud effects:



Due to e- induced gas desorption from the walls of the beam screen the vacuum pressure is increased by several orders of magnitude.

The electrons near the center of the vacuum chamber are attracted by the electric field of the beam and accumulate ("pinch") inside the proton beam during a bunch passage. They can cause beam instabilities, emittance growth, even beam loss, and poor lifetime.

The energetic electrons heat the surfaces that they impact. Only a limited cooling capacity is available for the additional heat load due to the electron cloud.







ECloud simulates the build up of the electron cloud.

- The ECLOUD simulation includes the electric field of the beam, arbitrary magnetic fields, the electron space charge field, and image charges.
- As input numbers, the code requires various beam parameters, surface properties: secondary emission yield (SEY), the vacuum chamber geometry and the type of magnetic field.



Therapy Selecthodology



Set A "LPA Satellite Scenario"		Set B "LPA Nominal"	
SEY	Bunch spacing	SEY	Bunch spacing
1.1 - 1.7	50 ns	1.1 - 1.7	50 ns
Nb: 1 x 10 ¹¹ – 5 x 10 ¹¹		Nb: 1 x 10 ¹¹ – 5 x 10 ¹¹	
Bunch Profile: Flat		Bunch Profile: Flat	
Set C "Scan Buch Spacing"		Set D "Scan Buch Spacing"	
	an Baon opaoing		
SEY	Bunch spacing	SEY	Bunch spacing
SEY 1.1 - 1.7	Bunch spacing 5ns - 50 ns	SEY 1.1 - 1.7	Bunch spacing 5ns - 50 ns
SEY 1.1 - 1.7 Nb: 6 x	Bunch spacing 5ns - 50 ns 10 ¹⁰ – 2.3 x 10 ¹¹	SEY 1.1 - 1.7 Nb: 6 x	Bunch spacing 5ns - 50 ns 10 ¹⁰ – 2.3 x 10 ¹¹









Average Heat Load - 1st Batch - SEY = 1.3





Average Heat Load - 1st Batch - SEY = 1.5









Average Heat Load - 1st Batch - SEY = 1.7









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Average Heat Load - 1st Batch -SEY = 1.3

























Average Heat Load - 1st Batch - SEY = 1.5 - Bunch Spacing = 5 ns



Average Heat Load - 1st Batch - SEY = 1.7 - Bunch Spacing = 5 ns





Conclusions

Conclusions:

- Heat load for 1st & 2nd batch almost the same.
- Satellite Scenario:

for SEY = 1.1 Heat load with satellites and without satellite almost the same.

for SEY > 1.1 The satellite scenario has a slightly higher heat load than the nominal one, for satellites there is a minimum in the heat load.

- Scan Bunch Spacing Flat Bunch Profile: For any SEY, bunch spacing of 50 ns has the lowest heat load.
- Scan Bunch Spacing Gaussian Bunch Profile:
 Gaussian bunch profile seems to have a higher heat load than a longer flat bunch profile.

Future work

✤ Compare heat load of the scan of bunch spacing for Gaussian bunches with σ_z =7.55 cm and longer flat bunches with I_b = 41 cm.

Simulate PS and SPS experiments (later).

Study the increase of the Pressure in SPS due to electron cloud.

Compare real LHC data with simulation (maybe the next year!?).

References

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